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On the analysis of solid and fluid dissipation in MEMS resonators

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DIFFERENT SOURCES OF DISSIPATION

Quality factor Q

Example: Tang resonator



solid/surface damping: internal friction, thermoelastic damping (resonators)





KNUDSEN NUMBER AND FLOW MODELS

Knudsen number Kn = λ/L

λ: mean free path of moleculesL: characteristic length scale

 λ =0.069 µm at SATP, λ ~1/p



Kn ≤ 10⁻³

- Navier-Stokes equations (no-slip):
- Navier-Stokes equations (slip):
- Transition regime:
- Free molecular flow:

10⁻³ ≤ Kn ≤ 10⁻¹

 $10^{-1} \le Kn \le 10$

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Kn > 10
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A. Frangi, Dissipation in MEMS, Pavia, September 26, 2011

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1. Fluid damping

- Continuum regime
- Rarefied (free molecule) regime

2. Solid damping

- Thermoelastic dissipation
- Anchor losses
- Surface losses



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Navier-Stokes equations (no-slip): Kn ≤ 10⁻³

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 $10^{-3} \le Kn \le 10^{-1}$

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Full Navier-Stokes model and simplifications ÓU $\frac{\partial \mathbf{u}}{\partial \mathbf{u}} + \rho \mathbf{u} \cdot \nabla \mathbf{u} = -\nabla p + \eta \Delta \mathbf{u}$ $- + \mathbf{u} \cdot \nabla \rho + \rho \nabla \cdot \mathbf{u} = 0$ **Reynolds** number Re = UL/v (U typical speed, L typical dimension, v kinematic viscosity) if Re << 1 neglect non-linear convective terms in Navier Stokes Mach number M = U/c (U typical speed, c speed of sound) if M << 1 set $\nabla u = 0$ (incompressibility) in Navier-Stokes Stokes number St = fL^2/v (f vibration frequency) if St << 1 neglect inertia terms in Navier-Stokes Example of biaxial accelerometer (SI units): $L \sim 2.6 \times 10^{-6} \text{ m}; \text{ f} = 4400 \text{ Hz}; \text{ v} = 1.5 \times 10^{-5}; \text{ U} \sim 2 \pi \text{ fD};$ D < 1/10 L (D amplitide of oscillation) U ~ 7×10⁻³ Re ~ 10⁻³ M ~ 7×10⁻⁴ St ~ 7×10⁻³

Incompressible (quasi-static) Stokes formulation

Image: Solution of the study of Navier-Stokes, Stokes, and Reynolds solutions for damping coefficients. 8 Image: Model problem for the study of Navier-Stokes, Stokes, and Reynolds solutions for damping coefficients. 8 Image: Model problem for the study of Navier-Stokes, Stokes, and Reynolds solutions for damping coefficients. 8



STOKES PROBLEM BY BEM: MVT and slip BC 9 $\nabla p(\mathbf{x}) - \eta \Delta \mathbf{u}(\mathbf{x}) = \mathbf{0}$ $\nabla \cdot \mathbf{u}(\mathbf{x}) = 0$ in Ω $\mathbf{u}(\mathbf{x}) = \mathbf{g}(\mathbf{x}) - c_t \mathbf{t}^S(\mathbf{x})$ on S $\sim c_t := \frac{2-\sigma}{\sigma} \frac{\lambda}{n}$ t tractions, t^S tractions projected on surface $\mathbf{t}^{S}(\mathbf{x}) = [\mathbb{1} - \mathbf{n}(\mathbf{x}) \otimes \mathbf{n}(\mathbf{x})] \cdot \mathbf{t}(\mathbf{x})$ Bounday Integral Equation Approach $\mathbf{g}(\mathbf{x}) - \frac{c_t}{2} \mathbf{t}^S(\mathbf{x}) - \frac{\gamma}{n} \frac{1}{2} \mathbf{t}(\mathbf{x}) = \int_{S} \left\{ \boldsymbol{\mathcal{V}}(\mathbf{r}) \cdot \mathbf{t}(\mathbf{y}) + c_t \left[\boldsymbol{\mathcal{K}}(\mathbf{r}) \cdot \mathbf{n}(\mathbf{y}) \right] \cdot \mathbf{t}^S(\mathbf{y}) \right\}$ $+\frac{\gamma}{n}\left(\left[\mathbf{n}(\mathbf{x})\cdot\boldsymbol{\mathcal{K}}(\mathbf{r})\right]\cdot\mathbf{t}(\mathbf{y})-c_{t}\left[\mathbf{n}(\mathbf{x})\cdot\boldsymbol{\mathcal{W}}(\mathbf{r})\cdot\mathbf{n}(\mathbf{y})\right]\cdot\mathbf{t}^{S}(\mathbf{y})\right)\right\}\mathrm{d}S_{y}$ Code licensed to: •Franci A., Tausch J., Engineering Analysis with Boundary Elements, 2005 Frangi A., Engineering Analysis with Boundary Elements, 2005 •Frangi A., Mechanics Research Communications, 2006 •Frangi A. et al., International J. Numerical Methods in Engineering, 2006

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Mach number M = U/c (U typical speed, c speed of sound) if M << 1 set $\nabla \cdot u = 0$ (incompresibility) in Navier-Stokes

Stokes number St = fL^2/v (f vibration frequency) if St << 1 neglect inertia terms in Navier-Stokes

Example of biaxial accelerometer (SI units): $L \sim 2.6 \times 10^{-6} \text{ m}; f = 4400 \text{Hz}; v = 1.5 \times 10^{-5}; U \sim 2\pi \text{fD};$ D < 1/10 L (D amplitide of oscillation) $U \sim 7^{\times}10^{-3}$ Re ~ 10⁻³ M ~ 7[×]10⁻⁴ St ~ 7[×]10⁻³



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Incompressible frequency-domain Stokes formulation

EXAMPLE (J.WHITE and coll.,MIT)



Finger gap	$2.88 \mu \mathrm{m}$
Finger length	$40.05 \mu { m m}$
Finger overlap	$19.44 \mu \mathrm{m}$
Center plate	$54.9 imes 19.26 \mu \mathrm{m}^2$
Side plate1 $\times 2$	$28.26 imes 89.6 \mu \mathrm{m}^2$
Side plate 2 $\times 4$	$11.3 imes 40.5 \mu \mathrm{m}^2$
Thickness	$1.96 \mu { m m}$
Substrate gap	$2\mu\mathrm{m}$
Truss length	$78 \mu { m m}$
Truss width	$13 \mu { m m}$

Drag force (pN)	Steady	Unsteady
Bottom	508.75	510.72
Side	284.84	294.50
Тор	102.31	142.8
Total	895.9	948.02



•Frangi A. Bonnet M., CMES, 2010



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Kn > 10

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BGK MODEL FOR BOLTZMANN EQUATION

 $\rho = \int_{\mathbb{R}^3} f d\boldsymbol{\xi} \qquad \text{on location } f(\boldsymbol{x}, \boldsymbol{\xi}) : \text{ma}$ $\rho \mathbf{v} = \int_{\mathbb{R}^3} f \boldsymbol{\xi} d\boldsymbol{\xi} \qquad \text{on location } f(\boldsymbol{x}, \boldsymbol{\xi}) = f(\boldsymbol{\xi})$ $\rho \mathbf{v} = \int_{\mathbb{R}^3} f \boldsymbol{\xi} d\boldsymbol{\xi} \qquad \text{on location } f(\boldsymbol{\xi}) = \mathbf{v} |^2 d\boldsymbol{\xi}$ $\sigma = \int_{\mathbb{R}^3} f(\boldsymbol{\xi} - \boldsymbol{v}) \otimes (\boldsymbol{\xi} - \boldsymbol{v}) d\boldsymbol{\xi}$

 $f(x, \xi)$: mass density probability depends on location x and molecular velocity ξ

mass density probability for a gas at rest

$$f_0 = \frac{\rho_0}{(2\pi \mathcal{R} T_0)^{3/2}} \exp\left(-\frac{|\boldsymbol{\xi}|^2}{2\mathcal{R} T_0}\right)$$

rest Maxwellian







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TEST PARTICLE MONTE CARLO METHOD

 Δ **q** denotes the linear momentum change of one molecule due to one collision and **w** the instant velocity of the shuttle,

The total dissipation induced by a single molecule before exiting the analysis domain through an in-flow surface is







Typical velocity of shuttle never exceed fractions of m/s and is always << thermal velocity of molecules

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FREE MOLECULE FLOW

 $f(x, \xi)$: mass density probability depends on location x and molecular velocity ξ

 $\frac{\partial f}{\partial t} + \boldsymbol{\xi} \cdot \nabla f = 0$

collisions between molecules neglected

for molecules coming from other MEMS surfaces:

$$f(\mathbf{x}, \boldsymbol{\xi}, t) = f(\mathbf{y}, \boldsymbol{\xi}, t - \frac{r}{\xi}) \qquad \mathbf{y} = \mathbf{x} + \mathbf{r}, \ \mathbf{r} = -r\frac{\boldsymbol{\xi}}{\xi}$$

for molecules coming from far field region:

$$f(\mathbf{x}, \boldsymbol{\xi}) = f_0(\boldsymbol{\xi}) = \frac{\rho_0}{(2\pi \mathcal{R} T_0)^{3/2}} \exp\left(-\frac{|\boldsymbol{\xi}|^2}{2\mathcal{R} T_0}\right)$$

x n(x)

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Diffuse model for molecules re-emitted from surfaces

$$f(\mathbf{x}, \boldsymbol{\xi}) = \frac{\rho_w(\mathbf{x})}{(2\pi \mathcal{R} T_w(\mathbf{x}))^{3/2}} \exp\left(-\frac{|\boldsymbol{\xi} - \mathbf{w}(\mathbf{x})|^2}{2\mathcal{R} T_w(\mathbf{x})}\right) \quad \text{for} \quad (\boldsymbol{\xi} - \mathbf{w}) \cdot \mathbf{n} > 0$$
$$\rho_w(\mathbf{x}) = \left(\frac{2\pi}{\mathcal{R} T_w(\mathbf{x})}\right)^{1/2} \int_{\mathbb{R}^3, (\boldsymbol{\xi} - \mathbf{w}) \cdot \mathbf{n} < 0} \left| (\boldsymbol{\xi} - \mathbf{w}(\mathbf{x})) \cdot \mathbf{n}(\mathbf{x}) \right| f(\mathbf{x}, \boldsymbol{\xi}) \mathrm{d}\boldsymbol{\xi}$$



FREE MOLECULE FLOW: LOW FREQUENCY LIMIT

$$J(\mathbf{x},\omega) = \sqrt{\pi} \tilde{\mathbf{g}}(\mathbf{x}) \cdot \mathbf{n}(\mathbf{x}) - \frac{2}{\pi} \int_{S^+} J(\mathbf{y},\omega) (\mathbf{r} \cdot \mathbf{n}(\mathbf{x})) (\mathbf{r} \cdot \mathbf{n}(\mathbf{y})) \frac{1}{r^4} T_3(i\tilde{\omega}r) dS + \frac{4}{\pi} \int_{S^+} (\mathbf{r} \cdot \tilde{\mathbf{g}}(\mathbf{y})) (\mathbf{r} \cdot \mathbf{n}(\mathbf{x})) (\mathbf{r} \cdot \mathbf{n}(\mathbf{y})) \frac{1}{r^5} T_4(i\tilde{\omega}r) dS$$

$$T^{(3)}(0) = 1/2$$

 $T^{(4)}(0) = 3\sqrt{\pi}/8.$

molecules at the wall

Limit case:

$$\frac{\omega}{\sqrt{2\mathcal{R}T}}L \ll 1$$

$$\begin{split} J(\mathbf{x}) = &\sqrt{\pi} \tilde{\mathbf{g}}(\mathbf{x}) \cdot \mathbf{n}(\mathbf{x}) \\ &- \frac{1}{\pi} \int_{S^+} J(\mathbf{y}) \big(\mathbf{r} \cdot \mathbf{n}(\mathbf{x}) \big) \big(\mathbf{r} \cdot \mathbf{n}(\mathbf{y}) \big) \frac{1}{r^4} \mathrm{d}S \\ &+ \frac{3}{2} \frac{1}{\sqrt{\pi}} \int_{S^+} \big(\mathbf{r} \cdot \tilde{\mathbf{g}}(\mathbf{y}) \big) \big(\mathbf{r} \cdot \mathbf{n}(\mathbf{x}) \big) \big(\mathbf{r} \cdot \mathbf{n}(\mathbf{y}) \big) \frac{1}{r^5} \mathrm{d}S \end{split}$$

J(x): normalised flux of

 $\mathbf{n}(\mathbf{x})$

Quasi static approximation: radiosity equation

•Frangi A., PAMM Proc. Appl. Math. Mech., 2008 •Frangi A., Ghisi A., Coronato L., Sensor & Actuators, 2009 •Frangi A., Engineering Analysis with Boundary Elements, 2009

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Qinetiq MAGNETOMETER





SEM of magnetometer structure

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solid/surface damping: internal friction, thermoelastic damping (resonators), 100000 → Q (fit) 10000 –**□**– Q (-3dB) Quality factor Q 1000 100 10 0.01 0.1 10 0.0001 0.001 1 10d Pressure [mbar] fluid damping: rarefied regime (gyroscopes)

fluid damping: continuum regime (accelerometers)

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Example



Global, Flexible, On demand and Resourceful Timing IC & MEMS Encapsulated System



Go4Time will target the realization of a generic miniature timing module relying on the combination of an integrated circuit together with different MEMS resonators assembled hermetically in a single package **V**TT







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Thermoelastic damping



Zener's solution for rectangular beams: 98.6% of dissipation occurs through the first bending mode

 k_{T} : thermal conductivity

h: beam thickness

$$Q_{TED} = \frac{C\rho}{\alpha^2 TE} \frac{f^2 + f_0^2}{f \cdot f_0}$$

E: Young's modulus *f*: resonance frequency

relaxation rate

$$f_0 = \frac{\pi}{2} \frac{k_T}{C\rho} \frac{1}{h^2}$$

•Ardito R., Comi C., Corigliano A., Frangi A., Meccanica, 2008











Simulation of anchor losses

Case of study: VTT extensional resonator (resonates according to the first axial mode of the thin beam)



Assume that the elastic waves scattered through the anchor are dissipated in the support (which is generally much larger than the resonator itself)

How to simulate this "dispersion"?

Preferred strategy. Use FEM for the resonator, truncate at finite distance and use:

- Absorbing Boundary Conditions (ABC)
- Perfectly Matched Layers (PML)
- Coupling with Boundary Elements

 $Q = 2\pi |\omega|/(2Im(\omega))$

where ω is the (complex) frequency of the mode corresponding to the resonating mode of the MEMS with no substrate

David S. Bindel and Sanjay Govindjee, Int. J. Numer. Meth. Engng 2005;





Simulation of anchor losses

Challenges: •migrate to 3D •correct choice (calibration) of parameters











Dissipation in bending modes

β	3	4	5	ref.[14]	ref.[11]
$Q \ (W_{\infty} = 700, \ N_{el} = 57453)$	324323	318715	316061	317500	296448
$Q \ (W_{\infty} = 700, \ N_{el} = 118785)$	325034	319381	316712	317500	296448
$Q \ (W_{\infty} = 700, \ N_{el} = 143118)$	325702	320011	317328	317500	296448
$Q \ (W_{\infty} = 800)$	318016	316103	315439	317500	296448







Effects of anchor losses

Piezotransduced Single-Crystal Silicon BAW Resonators

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experimental values: v=0.06 Q=20000 v=0.28 Q=3500

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- Surface losses ...interfaces?

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Experimental evidence

IEEE ELECTRON DEVICE LETTERS, VOL. 25, NO. 4, APRIL 2004



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Fig. 1. Square-extensional microresonator ($f_0 = 13.1$ MHz and $Q = 130\,000$). (a) Schematic of the resonator showing the vibration mode in the expanded shape and biasing and driving setup. (b) SEM image of the resonator.

piezoelectric transduction (very thin AIN layer)

Piezoelectrically transduced Single-Crystal-Silicon Plate Resonators

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Olli Holmgren and Kimmo Kokkonen Department of Applied Physics Helsinki University of Technology Espoo, Finland



Figure 1. Micrographs of resonators A and B. The thickness of the resonators is 20 μ m.

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Experimental evidence on a simpler problem

Q=20000 All w=40um trench Mo Mo Mo Mo Mo Mo Mo Si Si W_{br}=20um L_{pz}=310 um W_{pz}=30 um h_{pz}=500 nm L_{pz}=20 um L=320um

Figure 1. Micrograph of a wire-bonded resonator. The beam dimensions are $L \times w \times h$, and the piezolayer size is $L_{pz} \times w_{pz} \times h_{pz}$. L_{br} and w_{br} denote the anchor dimensions.

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A 12 MHz micromechanical bulk acoustic mode oscillator

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